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Passivated Edge Technology (PET): Edge Passivation for Industrial Solar Cell Applications

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pv magazine Webinar July 10, 2023 www.ise.fraunhofer.de

Fraunhofer Institute for Solar Energy Systems (ISE)

Freiburg im Breisgau, Germany



Fraunhofer ISE

- Founded in 1981
- Largest solar energy research institute in Europe
- About 1400 employees
- Budget 2022: € 107.0 million (20% industry)



Fraunhofer Institute for Solar Energy Systems (ISE)

Industry Partnerships





What Is Edge Recombination?

Edge recombination differs by edge region^[1]





[1] S. Glunz et al., 29th IEEE PVSC, 2002.

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What Is Edge Recombination?

Edge recombination differs by edge region^[1]

Three regions

- Highly-doped emitter (++) surface
 - "Regular" surface recombination with ideality factor n = 1

Space charge region (SCR) surface

- " j_{02} "-recombination" with n = 2
- Bulk surface
 - "Regular" surface recombination with n = 1



 j_{01} : dark saturation current density with ideality factor n = 1 j_{02} : dark saturation current density with ideality factor n = 2 S_{eff} : effective surface recombination velocity

edge



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Motivation Why Do We Need Edge Passivation?

Simulation results on bifacial PERC shingle solar cells^[1]



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Why Do We Need Edge Passivation?

Simulation results on bifacial PERC shingle solar cells^[1]

- Edge passivation boosts output power density / efficiency
 - The smaller the cell width is, the larger is the benefit
 - For 25 mm cell width \rightarrow 1 mW/cm² gain with edge passivation





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Why Do We Need Edge Passivation?

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- Edge passivation boosts output power density / efficiency
 - The smaller the cell width is, the larger is the benefit
 - For 25 mm cell width \rightarrow 1 mW/cm² gain with edge passivation
- Suppression of "regular" bulk recombination j_{01}
 - Small gain in open-circuit voltage $V_{\rm oc}$





Why Do We Need Edge Passivation?

Simulation results on bifacial PERC shingle solar cells^[1]

- Edge passivation boosts output power density / efficiency
 - The smaller the cell width is, the larger is the benefit
 - For 25 mm cell width \rightarrow 1 mW/cm² gain with edge passivation
- Suppression of "regular" bulk recombination j_{01}
 - Small gain in open-circuit voltage V_{oc}
- Suppression of " j_{02} "-recombination at SCR
 - Significant gain in pseudo fill factor *pFF* (and thus in *FF*)





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Technologies

Native grown SiO₂ layer on cell edge^[1]





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Technologies

- Native grown SiO₂ layer on cell edge^[1]
- Emitter window that keeps space charge region away from edge^[2]





Technologies

- Native grown SiO₂ layer on cell edge^[1]
- Emitter window that keeps space charge region away from edge^[2]
- Edge surface field by through-wafer diffusion in saw streets^[3]





Technologies

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- Emitter window that keeps space charge region away from edge^[2]
- Edge surface field by through-wafer diffusion in saw streets^[3]
- Usage of organic solutions basing on Nafion^[4,5]





Technologies

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- Native grown SiO₂ layer on cell edge^[1]
- Emitter window that keeps space charge region away from edge^[2]
- Edge surface field by through-wafer diffusion in saw streets^[3]
- Usage of organic solutions basing on Nafion^[4,5]
- Passivated edge technology (PET)^[6]
 - Introduced by Fraunhofer ISE in 2019
 - Deposition/formation of dielectric passivation layer on cell edge
 - Performed after cell cutting



[5] W. Li et al., Adv. Energy and Sustain. Res., 2022. [6] P. Baliozian et al., IEEE J. Photovoltaics, 2020.



Milestones

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15

- 2018: Patent application (already granted in Germany and USA)
- 2019: First publications with application to bifacial **PERC** shingle solar cells^[1,2] using Al_2O_3 by atomic layer deposition (ALD)

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Milestones

Fraunhofer ISE

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- 2018: Patent application (already granted in Germany and USA)
- 2019: First publications with application to bifacial **PERC** shingle solar cells^[1,2] using Al_2O_3 by atomic layer deposition (ALD)
- 2021: First demonstration on silicon heterojunction (SHJ) half solar cells^[3]

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Milestones

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- 2021: First demonstration on silicon heterojunction (SHJ) half solar cells^[3]
- 2022/2023

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- First demonstration on tunnel-oxide passivated contact (TOPCon) shingle cells^[4]
- Transfer to high-throughput ALD tool^[5] and demonstration on **TOPCon** shingle cells^[6]

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(12)	Unite Lohmül	Elmar, D., 29110 Freiburg, DE; Preu, 110 Feilburg, DE: Ballocian, Buzant d States Patent er et al.	(10) Pater (45) Date	US011: DIS011: Of Pater	s of Semicor 108863B2 US 11,; it: N	508,	863 B
(12)	Lohmüller, Raif Dr. 73 Unite Lohmül SEMICO METHOI SEMICO PN JUNC	Elmar, D., 7910 Freiburg, DE; Preu, tith Freiburg, DE: Baliocian, Burant d States Patent er et al. SDUCTOR COMPONENT AND POR SINGULATING A SDUCTOR COMPONENT HAVING A TION	(10) Pater (45) Date (58) Field of CPC	M.: Physic US011: uS011: of Pater Classificath H01L 33 31/0216;	s of Semicor 508863B2 US 11,5 it; N m Search 702167; H011 H011, 31/021-	508, iov. 2	863 B 22, 202 2168; H0: 11L 31/06
(12) (54) (71)	Lohmüller, Raif Dr. 75 Unite Lohmül SEMICO PN JUNC Applicant:	Elmar, Dr., 7910 Freiburg, DE; Preu, tit Freiburg, DE; Baliozian, Buzant d States Patent er et al. SDUCTOR COMPONENT AND POR SINCULATING A SDUCTOR COMPONENT HAVING A TON Fraunhofe-Greellschuft zur Fraunhofe-Greellschuft zur Fraunhofe-Greellschuft zur	(10) Pater (45) Date (58) Field of CPC See appli	LISTIC Classification Classification 11/0216; 12/0216; 13/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216; 12/0216	s of Semicor 008863B2 US 11, it: N m Search /02167: H011 H011. 31/021- or complete s	508, 508, 508, 508, 508, 508, 508, 508,	863 B 22, 202 2168; H0: 11, 31/06 11, 31/08 11, 31/18 history.
(12) (54) (71)	Lohmüller, Raif Dr. 75 Unite Lohmül SEMICO SEMICO PN JUNC Applicant:	Elmar, Dr., 7910 Freiburg, DE; Preu, tit Feelburg, DE; Baliozian, Burant d States Patent er et al. NUCTOR COMPONENT AND FOR SINGLATING A NDUCTOR COMPONENT HAVING A TION Frauhofer-Gesellschaft zur Forderung der angewandten Forschung Z-, Manich (DE)	(10) Pater (45) Date (58) Field of CPC See appli	LSC III Classification Classification 11/0216; 12/0216; 13/0216; 13/0216; 13/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/0216; 14/025	s of Semicor iiiiiiiiiiiiiiiiiiiiiiiiiiiiiiiiiiii	508, 100, 1 100, 100,	863 B 22, 202 2168; H0: 51L 31/06 history.
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[5] M. Hofmann et al., Solar RRL, to be published. [6] E. Lohmüller et al., Solmat, 2023.

Milestones

Fraunhofer ISE

- 2018: Patent application (already granted in Germany and USA)
- 2019: First publications with application to bifacial **PERC** shingle solar cells^[1,2] using Al₂O₃ by atomic layer deposition (ALD)
- 2021: First demonstration on silicon heterojunction (SHJ) half solar cells^[3]
- 2022/2023
 - First demonstration on tunnel-oxide passivated contact (TOPCon) shingle cells^[4]
 - Transfer to high-throughput ALD tool^[5] and demonstration on TOPCon shingle cells^[6]

Others

- 2020 (CEA-INES): First demonstration on SHJ shingle cells^[7]
- 2023 (Singulus): Generis PET tool^[8]

PET approach is "industry ready" and compatible with **PERC, TOPCon,** and **SHJ** cells





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FHK-SK: ISE-PUBLIC

P. Baliozian et al., IEEE J. Photovolt., 2020.
 P. Baliozian et al., Photovoltaics Int., 2019.
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[6] E. Lohmüller et al., Solmat, 2023.
[7] S. Harrison et al., EU-PVSEC, 2020.
[8] Singulus, press release, 2023.

Cell Cutting Technologies

- "Conventional"
 - Laser scribe and mechanical cleaving (LSMC)^[1]
- "Low-damage"
 - Thermal laser separation (TLS)^[2]
 - Laser induced cutting (LIC)^[3]
 - Laser direct cleaving (LDC)^[4]
 - 45° rotated silicon brick and wafer fabrication^[5]





TLS @ Fraunhofer ISE: microDICE (3D-Micromac)



Low-Damage Cell Cutting and Edge Passivation by PET^[1-3]

Host solar cells with shingle layout





Low-Damage Cell Cutting and Edge Passivation by PET^[1-3]

- Host solar cells with shingle layout
- Separation into cell stripes
 - Increased perimeter-to-area ratio
 - Edge recombination due to cut edges^[4-6]





Low-Damage Cell Cutting and Edge Passivation by PET^[1-3]

- Host solar cells with shingle layout
- Separation into cell stripes
 - Increased perimeter-to-area ratio
 - Edge recombination due to cut edges^[4-6]
- Edge passivation by PET
 - ALD Al_2O_3
 - Annealing

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Low-Damage Cell Cutting and Edge Passivation by PET^[1-3]

- Host solar cells with shingle layout
- Separation into cell stripes
 - Increased perimeter-to-area ratio
 - Edge recombination due to cut edges^[4-6]
- Edge passivation by PET
 - ALD Al_2O_3
 - Annealing

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Shingling of cells into shingle strings^[7] and ...





[1] P. Baliozian et al., IEEE J. Photovoltaics, 2020. [2] E. Lohmüller et al., Prog. Photovolt.: Res. Appl., 2023 © Fraunhofer ISE [3] E. Lohmüller et al., Solmat, 2023 FHK-SK: ISE-PUBLIC [4] K. R. Mcintosh, PhD thesis, UNSW, 2001.

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Passivated Edge Technology (PET): TOPCon Shingle Solar Cells

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¹Fraunhofer Institute for Solar Energy Systems (ISE), Heidenhofstraße 2, 79110 Freiburg, Germany ²now with VDMA Photovoltaic Equipment, Lyoner Str. 18, 60528 Frankfurt am Main, Germany ³Plasma Electronic GmbH, Otto-Lilienthal-Straße 2, 79395 Neuenburg, Germany ⁴The Solaria Corporation, 45700 Northport Loop E, Fremont, CA 94538, USA

More information on this, see E. Lohmüller et al., "Thermal laser separation and high-throughput layer deposition for edge passivation for TOPCon shingle solar cells", Sol. Energy Mater. Sol. Cells 258, 112419, DOI: 10.1016/j.solmat.2023.112419.

Supported by:

Federal Ministry for Economic Affairs and Climate Action

on the basis of a decision by the German Bundestag

Approach TOPCon Host Cells

- Industrial TOPCon host solar cells
 - Bifacial six-shingle metallization design
 - Full-square format
 - 158.75 mm edge length
 - Shingle cell width: 26.46 mm
 - Mean energy conversion efficiency of 22.0%*



*Tested with GridTouch in a monofacial setup on black foil





Experimental

Schematic Process Sequence

Comparison between

Gr1 vs Gr2

LSMC

TLS
 Lab-scale thermal ALD (T-ALD) Al₂O₃

	Gr1	Gr2			
	TOPCon host cells				
	LSMC (rear)	TLS (front)			
	I-V te	esting			
	Al ₂ O ₃ deposition				
БП	T-ALD (8 nm, 180°C)				
ـــ	Hotplate anneal (250°C)				
	I-V te	esting			



Experimental

Schematic Process Sequence

Comparison between

Gr1 vs Gr2

LSMC

TLS
 Lab-scale thermal ALD (T-ALD) Al₂O₃

Gr3

 Transfer to high-throughput plasma-enhanced ALD (PE-ALD) Al₂O₃

	Gr1		Gr2	Gr3		
			TOPCon host cells			
	LSMC (rear)		TLS (fro	nt)		
PEI	T-ALD	PE-ALD (6 nm, 80°C)				
	J Hotplat	(Hotplate anneal (325°C)				
	I-V testing					



High-Throughput Al₂O₃ Layer Deposition

Processing with Stacked Shingle Cells

High-throughput PE-ALD Al₂O₃

- Shingle stacks
- Current run duration: 1 hour
 Capactity: 60.750 shingle cells per run
 → 0.5 GW_p/year
- Run duration of around 15 min possible by hardware and process optimization
 → 2 GW_p/year





Results Comparison Laser Cutting Technology

• TLS in Gr2/3 yields $\Delta \eta = +0.2\%_{abs}$ more efficient shingle cells





ISE

Results

Comparison ALD of Al₂O₃ Passivation Layer

• TLS in Gr2/3 yields $\Delta \eta = +0.2\%_{abs}$ more efficient shingle cells

PET yields

• $\Delta \eta = +0.4\%_{abs}$ for LSMC and TLS • $\Delta \eta = +0.5\%_{abs}$ for PE-ALD

TLS + PET:

Up to $\Delta \eta = +0.7\%_{abs}$ compared to shingle cells without edge passivation cut by LSMC





Results

Comparison ALD of Al₂O₃ Passivation Layer

- TLS in Gr2/3 yields Δη = +0.2%_{abs} more efficient shingle cells
- PET yields
 - $\Delta \eta = +0.4\%_{abs}$ for LSMC and TLS • $\Delta \eta = +0.5\%_{abs}$ for PE-ALD

TLS + PET:

Up to $\Delta \eta = +0.7\%_{abs}$ compared to shingle cells without edge passivation cut by LSMC



🗾 Fraunhofer

ISE

SOLARIA



Summary



Low-damage cutting and high-throughput Al₂O₃ deposition is very promising for industrialization of the PET



SOLARIA PLASMA ELECTRONIC Fraunhofer





Thank You for Your Attention!

Contact

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Supported by:



on the basis of a decision by the German Bundestag

The activities have been financially supported by the German Federal Ministry for Economic Affairs and Climate Action within the research projects "PV-BAT400" (grant number 0324145) and "GutenMorgen" (03EE1101A).
High quality cell cutting with Thermal Laser Separation

PV Magazine Webinar, 10 July, 2023



3D-Micromac – The Specialist in Laser Micromachining

Key	Facts
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Services



Machine	Base
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 » Founded in 2002
 » 180 employees
 » Based in Chemnitz, Germany
 » Branch offices in US and Taiwan

- » Feasibility studies & process
 development in-house
 » Production of limited lots and
 ramp-up production
 » Worldwide sales & service network
- > 600 installations worldwide
- > 50 systems in semi industry
- > 150 systems in glass/display
- > 30 systems in microdiagnostics
 - > 110 systems in photovoltaics
- > 30 systems in roll-to-roll production



Target Markets & Products





Laser Technology for Photovoltaics





TLS-cut shingled-cells

Laser structuring of flexible TFPV

- microCELL[™] MCS and microCELL[™] TLS: Enabling best-in-class throughput & unmatched edge quality in solar cell cutting
 - Patented TLS technology
 - For half- and shingled PV cells
 - Free-form cuts possible
- microFLEX™ PV: Laser structuring of flexible and organic thin-film solar cells in P1, P2, P3, and P4/PT





Content

1. Motivation

- 2. Thermal Laser Separation explained
- 3. Advantages for cell and module manufacturing
- 4. Economic Impact
- 5. Summary



hhile K•h

Motivation

Standard industry process:

- Laser ablation "scribe and break"
 - Trench 40 60 % of the cell's thickness
 - Subsequent mechanical breaking
- Limitations in:
 - Throughput
 - Process quality
 - Particle generation
 - Electrical and mechanical performance





Thermal Laser Separation (TLS)

• Starting point (and optional straightness) defined by scribe

• TLS is a cleaving process, initiated by heat and cooling





TLS-Cutting Technology





Main Properties of TLS-Dicing[®]



Resizing of Si (ø 300 to 200 mm, Si 775 µm), Courtesy of Fraunhofer Gesellschaft Spiral of Si (ca. 400 μm thick) after TLS-cleave and I-Scribe



TLS-Cutting vs. Scribe and Break – Results Breaking Edge

Cross sectional view on solar cell after cutting

Conventional process: scribe and break





→ Extensive chipping
→ Very rough structure

- \rightarrow Very smooth structure
- \rightarrow No chipping visible
- → perfect surface for repassivation approaches



TLS-Cutting – Mechanical Performance

Goal

• Compare mechanical strength of a fullcell cut by TLS and scribe and break

Measurement Method

- Measuring the mechanical strength by using the 4-point bending test
- Tests done by Fraunhofer Institute



FE-Model 4-point-Bending

4-point-bending (mc-Si Wafer)



Results Mechanical Strength



→ Courtesy Fraunhofer CSP

Solar cells



Module laminates



Comparison of Fracture Origin

Fracture Origin:

EL pictures after testing | brightness and contrast adjusted

Surface

Edge

Full Cells (reference)



surface defects \rightarrow pads



surface defects \rightarrow pads



mostly edge defects \rightarrow cutting process

→ Courtesy Fraunhofer CSP



TLS and Economic Benefit for Module Manufacturing







Enabling best-in-class throughput & unmatched edge quality in solar cell cutting

- Patented TLS technology
- For half- and shingled PV cells
- Free-form cutting





microCELL MCS – Next Generation Cell Cutting

- Worldwide install base > 15 GW
- Format and pattern adjustments via flexible chuck design
- up to five process positions: exchangeable, retrofitable, expandable
 → fully flexible from 1/2 cells to 1/6 cell stripes
- Wafer recognition by camera
- Scanner-based initial scribe
- Cleave: adjustable on motorizes stages
- > 6,000 wph for 1/2 to 1/6 cut cells
- Contactless and ablation-free cutting
- Improved module performance/less power degradation





TLS-Cutting provides excellent cleaving results in combination with higher yield and throughput.



Thank you for your attention!

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GENERIS PET Industrialized High Throughput Solution for Passivated Edge Technology

July 10th, 2023





Outline

- Introduction SINGULUS TECHNOLOGIES AG
- GENERIS PET for Edge Passivation
- Summary
- Contact ullet

SINGULUS TECHNOLOGIES AG



Introduction SINGULUS TECHNOLOGIES AG

SINGULUS Technologies AG - Substantial Technologies for different Business Markets



SINGULUS TECHNOLOGIES AG

July 10th,2023



- Established:
- Employees:
- Research & Development
- Consulting
- Engineering & Design
- Production

- 1995 (Buyout at Merger Balzers/Leybold) 354
 - Project Management
 - Installation/Commissioning
 - Service/Maintenance
 - Training







Introduction SINGULUS TECHNOLOGIES AG

Innovative Application and Equipment for efficient and resource saving production processes









Plasma Etching

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Wet Chemical Treatment









Improvement of Module Efficiency by Edge Passivation

Standard (Full) Cell



Cell cut after finished cell fabrication





- without PET
- Increased efficiency on module level

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GENERIS PET Tool



SINGULUS TECHNOLOGIES AG

July 10th,2023

Features

- Industrialized High Volume Inline solution for deposition of edge cover layers for passivated edge technology (PET)
- **Excellent passivation properties** of edge cover layers enabling ullet
 - Compensation of recombination losses caused by cell cutting
 - Increased cell/module efficiency
- **Unique carrier design** for processing of all wafer and cut formats ullet(Halfcut, Multi-cut, Shingle cells) and simultaneous passivation of all cut edges
- Available as standard and advanced version depending on throughput requirements
- Retrofittable to existing fabs due to stand-alone machine design
- Fully automated carrier loading and unloading







Concept of Deposition



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Inline deposition of edge cover layers on vertically arranged wafer cuts (Halfcut, Multi-cut, Shingle cells)



Throughput GENERIS PET Tool (Standard)

Cut Format	1/2 cut	1/4 cut	1
Wafer cuts per carrier		48	00
Machine cycle time		20 mi	nute
Annual substrate throughput total (net)		~ 114	Mic
P net for annual throughput for G12	~ 600 MW	~ 300 MW	~ 1

Throughput GENERIS PET Tool (Advanced)

Cut Format	1/2 cut	1/4 cut	1
Wafer cuts per carrier		72	00
Machine cycle time		6 mir	utes
Annual substrate throughput total (net)		~ 562	. Mic
P net for annual throughput for G12	~ 3000 MW	~ 1500 MW	~ 1

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GENERIS PET Tool for Halfcut – Comparison Cost of Ownership

GENERIS PET Tool (Standard)

Cut Format	1/2 cut	Cut Format	1/2 cut
Annual substrate throughput total (net)	~ 114 Mio.	Annual substrate throughput total (ne	et) ~ 562 Mio.
P net for annual throughput for G12	~ 600 MW	P net for annual throughput for G12	~ 3000 MW
<section-header> CoO GENERIS PET (Standard) • Total cost per substrate for PET: ~ 0,01 €/substrate • Total cost per additional Wp with PET ~ 0,077 €/Wp</section-header>	the second secon	Store of the second	PET
		SINC	GULUS

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GENERIS PET Tool (Advanced)







Summary

- Industrialized high throughput solution for passivated edge technology
- Excellent passivation layer properties for increased efficiency on cell/module level
- Unique carrier design compatible for processing of all wafer and cut formats (Halfcut, Multi-cut, Shingle cells)
- **Retrofittable to existing fabs** due to stand-alone machine design
- Low CoO and machine payback time

SINGULUS TECHNOLOGIES AG

July 10th,2023









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SINGULUS TECHNOLOGIES AG











At The Cutting Edge of PV Technology: Matrix-Shingle Solar Modules

Evolut^[10]n Module Manufacturing Process





Solar Modules with Shingled Solar Cell Interconnection Evolut^[10]n





Ribbon / wire interconnection



Shingle solar cell interconnection ^[1]





Evolut^[10]n Matrix-Shingle Interconnection



Matrix-shingle module layout

- Introducing: half-cut shingle solar cells
- Creation of masonry-like structure
- Parallel Interconnection of solar cells in one row
- Serial interconnection of rows forming the module
- → Intrinsic serial-parallel interconnection of solar cells







elektrical layout: matrix of solar cells

Evolut^[10]n Revolut^[10]nary Module Aesthetics





Evolut^[10]n Revolut^[10]nary Module Aesthetics



Highly aesthetic solar modules

- Creating surfaces without obvious "PV-optic"
- Working with cell distances to create patterns

Add color

- Colored back sheets
- Combination with MorphoColor[®] on front glass
 - Developed by Fraunhofer ISE
 - Highly intensive and homogenous color
 - Optical transmission losses <10 %



Plain matrix-shingle

Patterned layout with (colored) back sheet

+ MorphoColor®

Evolut^[10]n Revolut^[10]nary Efficiency







sketches not to scale

Evolut^[10]n Revolut^[10]nary Efficiency



- 1. Electrical Advantages
 - No Ribbons
 - Reduced ohmic losses in module



→ X



sketches not to scale
Evolut^[10]n Revolut^[10]nary Efficiency



- 1. Electrical Advantages
 - No Ribbons
 - Reduced ohmic losses in module

2. Geometrical Advantages

- Reduction of inactive cell gaps
- Higher packing densities of solar cells







sketches not to scale

Evolut^[10]n Revolut^[10]nary Efficiency



1. Electrical Advantages

- No Ribbons
- Reduced ohmic losses in module

2. Geometrical Advantages

- Reduction of inactive cell gaps
- Higher packing densities of solar cells

3. Optical Advantages

- "No" shading from busbar metallization
- No shading from ribbons



► X

Ζ

► X



Ζ

v

Evolut^[10]n Revolut^[10]nary Efficiency



1. Electrical Advantages

- No Ribbons
- Reduced ohmic losses in module

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- Reduction of inactive cell gaps
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3. Optical Advantages

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sketches not to scale

© M10 Solar Equipment GmbH

4. PET









Evolut^[10]n Revolut^[10]nary Partial Shading Behavior

Significant increased shading resilience^[1,2,3]

- Parallel interconnections
- Lateral currents
- Fill factor effect

Comprehensive Monte Carlo simulations

- Rectangular shades
- Random clustered shades
- Comparison of
 - Matrix-shingle module, 300 shingle cells
 - String-shingle module, 300 shingle cells
 - Butterfly module, 120 half-cells
 - Commercial 60 full cell module









Matrix-Shingle Modules

Highly aesthetic, efficient* and shading resilient Solar Modules

Preferred Application: xIPV

*especially when combined with PET

www.m10solar.com 13

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Evolut^[10]n Module Manufacturing Process





Evolut^[10]n Module Manufacturing Process





Evolut^[10]n Module Manufacturing Process







Material	Process	Cost	Service-friendly
All solar cell formats:	■ consistent production ⇒ 12'000 cells/h	Less Manpower	Artificial Intelligence
M0 to M12+		 Less material consumption 	 European Service Network
 All types of cells like HJT, Perovskite, Tandem, TopCon, 	Flexibility in changeover		
	Lead-free process	 Less cleaning & maintenance 	

- bifacial ready!
- no ribbon, no flux



Configure your product, not your tools!



Agri Photovoltaics



Roof tiles



Thank you for your kind attention!

Vismal

M10 Industries AG

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10 July 2023

3:00 pm – 4:00 pm | BST, London 4:00 pm – 5:00 pm | CEST, Berlin 10:00 am – 11:00 am | EDT, New York City



Mark Hutchins Editor pv magazine



At the cutting edge of PV technology Q&A



Elmar Lohmüller Product Manager Fraunhofer ISE Thomas Kießling Sales Manager 3D-Micromac



Jan Krausmann Product Manager

Singulus Technologies

Nils Klasen

r Technology & Sales Manager gies M10



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Coming up next...

Thursday, 13 July 2023 4:00 pm – 4:00 pm CEST, Berlin, Paris, Madrid 10:00 am – 11:00 am EDT, New York City **Tuesday, 25 July 2023** 10:00 am – 11:00 am PDT, Los Angeles 1:00 pm – 2:00 pm EDT, New York City

Many more to come!

Reliability analysis of n-type modules

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Mark Hutchins Editor pv magazine

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